#### **Features**

- Fast Read Access Time 45 ns
- Low Power CMOS Operation
  100 μA max. Standby

20 mA max. Active at 5 MHz

- JEDEC Standard Packages
  28-Lead 600-mil PDIP
  32-Lead PLCC
  28-Lead TSOP and SOIC
- 5V ± 10% Supply
- High Reliability CMOS Technology 2,000V ESD Protection 200 mA Latchup Immunity
- Rapid<sup>™</sup> Programming Algorithm 100 µs/byte (typical)
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

### **Description**

The AT27C512R is a low-power, high performance 524,288 bit one-time programmable read only memory (OTP EPROM) organized 64K by 8 bits. It requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 45 ns, eliminating the need for speed reducing WAIT states on high performance microprocessor systems.

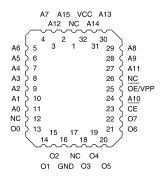
Atmel's scaled CMOS technology provides high speed, lower active power consumption, and significantly faster programming. Power consumption is typically only 8 mA in Active Mode and less than 10  $\mu$ A in Standby.

(continued)

### **Pin Configurations**

Pin Name	Function
A0 - A15	Addresses
O0 - O7	Outputs
CE	Chip Enable
OE /V <sub>PP</sub>	Output Enable/V <sub>PP</sub>
NC	No Connect

#### **PLCC Top View**



Note: PLCC Package Pins 1 and 17 are DON'T CONNECT.

PDIP, SOIC Top View

				7	
A15	$\Box$	1	28	Þ	VCC
A12	П	2	27	Þ	A14
Α7	$\Box$	3	26	Þ	A13
A6	П	4	25	Þ	A8
A5	q	5	24	Þ	A9
A4		6	23	Þ	A11
АЗ	d	7	22	Þ	OE/VPP
A2	q	8	21	Þ	A10
A1		9	20	Þ	CE
A0	$\Box$	10	19	Þ	O7
00	$\Box$	11	18	Þ	O6
01		12	17	Þ	O5
02	$\Box$	13	16	Þ	O4
GND	d	14	15	Þ	О3

TSOP Top View **Type 1** 

OE/VPP		22	21		Þ		A10
A9 🗆	23	24	19	20	Ĕ	CE	07
A13 🖳	25	26	17	18	Ĕ	06	O5
vcc □	27	28	15	16	Ĕ	04	О3
A12 A15	1	2	13	14	Ĕ	GND	O2
A6	3	4	11	12	Ĕ	01	00
A4 A3 5	5 7	6	9	10 8	6	A0 A2	A1

512K (64K x 8) OTP CMOS EPROM

0015H





### **Description** (Continued)

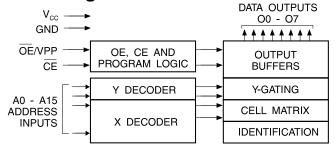
The AT27C512R is available in a choice of industry standard JEDEC-approved one-time programmable (OTP) plastic PDIP, PLCC, SOIC, and TSOP packages. All devices feature two-line control (CE, OE) to give designers the flexibility to prevent bus contention.

With 64K byte storage capability, the AT27C512R allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

#### **System Considerations**

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1  $\mu$ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V<sub>CC</sub> and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7  $\mu$ F bulk electrolytic capacitor should be utilized, again connected between the V<sub>CC</sub> and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

### **Block Diagram**



### **Absolute Maximum Ratings\***

Temperature Under Bias55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V (1)
Voltage on A9 with Respect to Ground2.0V to +14.0V (1)
V <sub>PP</sub> Supply Voltage with Respect to Ground2.0V to +14.0V <sup>(1)</sup>

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V<sub>CC</sub> + 0.75V dc which may overshoot to +7.0V for pulses of less than 20 ns.

### **Operating Modes**

Mode \ Pin	CE	OE/V <sub>PP</sub>	Ai	Outputs
Read	VIL	VIL	Ai	Dout
Output Disable	VIL	ViH	X <sup>(1)</sup>	High Z
Standby	V <sub>IH</sub>	X <sup>(1)</sup>	Χ	High Z
Rapid Program (2)	VIL	V <sub>PP</sub>	Ai	D <sub>IN</sub>
PGM Inhibit	VIH	Vpp	X <sup>(1)</sup>	High Z
Product Identification (4)	VIL	VIL	A9 = V <sub>H</sub> <sup>(3)</sup> A0 = V <sub>IH</sub> or V <sub>IL</sub> A1 - A15 = V <sub>IL</sub>	Identification Code

Notes: 1. X can be V<sub>IL</sub> or V<sub>IH</sub>.

2. Refer to Programming Characteristics.

3.  $V_H = 12.0 \pm 0.5 V$ .

4. Two identifier bytes may be selected. All Ai inputs are held low ( $V_{IL}$ ), except A9 which is set to  $V_H$  and A0 which is toggled low ( $V_{IL}$ ) to select the Manufacturer's Identification byte and high ( $V_{IH}$ ) to select the Device Code byte.





# **DC and AC Operating Conditions for Read Operation**

			AT27C512R									
		-45	-55	-70	-90	-12	-15					
Operating	Com.	0°C - 70°C										
Temp.(Case)	Ind.	-40°C - 85°C										
V <sub>CC</sub> Supply		5V ± 10%										

# **DC and Operating Characteristics for Read Operation**

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to $V_{CC}$		±1	μΑ
ILO	Output Leakage Current	$V_{OUT} = 0V$ to $V_{CC}$		±5	μΑ
lon	V <sub>CC</sub> <sup>(1)</sup> Standby Current	I <sub>SB1</sub> (CMOS), $\overline{\text{CE}} = \text{V}_{\text{CC}} \pm 0.3\text{V}$		100	μΑ
ISB	VCC ** Standby Current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5 $V$		1	mA
Icc	V <sub>CC</sub> Active Current	$\frac{f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA},}{CE} = V_{IL}$		20	mA
VIL	Input Low Voltage		-0.6	0.8	V
VIH	Input High Voltage		2.0	Vcc + 0.5	<b>V</b>
VoL	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
Vон	Output High Voltage	Ι <sub>ΟΗ</sub> = -400 μΑ	2.4		V

Note: 1. V<sub>CC</sub> must be applied simultaneously or before  $\overline{\text{OE}}/\text{V}_{PP}$ , and removed simultaneously or after  $\overline{\text{OE}}/\text{V}_{PP}$ .

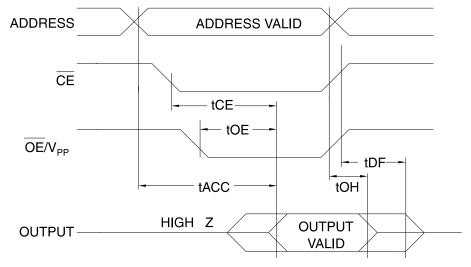
# **AC Characteristics for Read Operation**

		-	AT27C512R												
				45	-55 -70		-90		-12		-15				
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Units
tacc (3)	Address to Output Delay	$\overline{CE} = \overline{OE}/V_{PP}$ = $V_{IL}$		45		55		70		90		120		150	ns
t <sub>CE</sub> (2)	CE to Output Delay	$\overline{OE}/V_{PP} = V_{IL}$		45		55		70		90		120		150	ns
toe (2, 3)	OE/V <sub>PP</sub> to Output Delay	CE = VIL		20		25		30		35		35		40	ns
t <sub>DF</sub> (4, 5)	OE/V <sub>PP</sub> or CE High Output Float, which	to ever occurred first		20		20		25		25		30		35	ns
toH	Output Hold from Address, CE or OE/ whichever occurred		7		7		7		0		0		0		ns

Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.

3-138 AT27C512R =

# **AC Waveforms for Read Operation** (1)



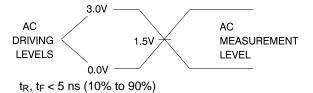
Notes: 1. Timing measurement reference level is 1.5V for -45 and -55 devices. Input AC drive levels are  $V_{IL}=0.0V$  and  $V_{IH}=3.0V$ . Timing measurement reference levels for all other speed grades are  $V_{OL}=0.8V$  and  $V_{OH}=2.0V$ . Input AC drive levels are  $V_{IL}=0.45V$  and  $V_{IH}=2.4V$ .

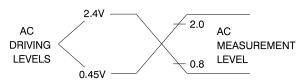
- 2. OE/V<sub>PP</sub> may be delayed up to t<sub>CE</sub> t<sub>OE</sub> after the falling edge of CE without impact on t<sub>CE</sub>.
- 3. OE/V<sub>PP</sub> may be delayed up to t<sub>ACC</sub> t<sub>OE</sub> after the address is valid without impact on t<sub>ACC</sub>.
- 4. This parameter is only sampled and is not 100% tested.
- Output float is defined as the point when data is no longer driven.

### **Input Test Waveforms and Measurement Levels**

For -45 and -55 devices only:

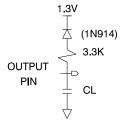
For -70, -90, -12, -15, and -20 devices:





 $t_R$ ,  $t_F < 20$  ns (10% to 90%)

### **Output Test Load**



Note: CL = 100 pF including jig capacitance, except for the -45 and -55 devices, where CL = 30 pF.

## **Pin Capacitance** (f = 1 MHz T = $25^{\circ}$ C)

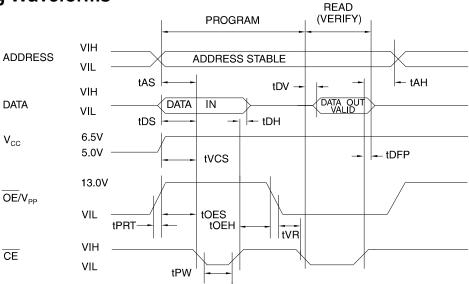
	Тур	Max	Units	Conditions
C <sub>IN</sub>	4	6	pF	$V_{IN} = 0V$
Cout	8	12	pF	V <sub>OUT</sub> = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.





**Programming Waveforms** 



Notes: 1. The Input Timing Reference is 0.8V for  $V_{IL}$  and 2.0V for  $V_{IH}$ .

2. toE and tDFP are characteristics of the device but must be accommodated by the programmer.

# **DC Programming Characteristics**

 $T_A = 25 \pm 5^{\circ}C$ ,  $V_{CC} = 6.5 \pm 0.25V$ ,  $\overline{OE}/V_{PP} = 13.0 \pm 0.25V$ 

		Test	Li	Limits		
Symbol	Parameter	Conditions	Min	Max	Units	
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μА	
VIL	Input Low Level		-0.6	0.8	V	
VIH	Input High Level		2.0	V <sub>CC</sub> + 1	V	
$V_{OL}$	Output Low Voltage	$I_{OL} = 2.1 \text{ mA}$		0.4	V	
VoH	Output High Voltage	$I_{OH} = -400 \mu A$	2.4		V	
ICC2	V <sub>CC</sub> Supply Current (Program and Verify)			25	mA	
I <sub>PP2</sub>	OE/V <sub>PP</sub> Current	$\overline{CE} = V_{IL}$		25	mA	
V <sub>ID</sub>	A9 Product Identification Voltage		11.5	12.5	V	

3-140 AT27C512R

### **AC Programming Characteristics**

 $T_A = 25 \pm 5$ °C,  $V_{CC} = 6.5 \pm 0.25$ V,  $\overline{OE}/V_{PP} = 13.0 \pm 0.25$ V

Sym-	Test	Liı	nits	Units
bol	Parameter Condtions* (1)	Min	Max	
tas	Address Setup Time	2		μS
toes	OE/V <sub>PP</sub> Setup Time	2		μS
toeh	OE/V <sub>PP</sub> Hold Time	2		μS
t <sub>DS</sub>	Data Setup Time	2		μS
tah	Address Hold Time	0		μS
tDH	Data Hold Time	2		μS
t <sub>DFP</sub>	CE High to Output Float Delay (2)	0	130	ns
tvcs	V <sub>CC</sub> Setup Time	2		μS
tpw	CE Program Pulse Width (3)	95	105	μS
t <sub>D</sub> V	Data Valid from CE (2)		1	μS
$t_{VR}$	OE/V <sub>PP</sub> Recovery Time	2		μS
tprt	OE/V <sub>PP</sub> Pulse Rise Time During Programming	50		ns

#### \*AC Conditions of Test:

Input Rise and Fall Times (10% to 90%).................. 20 ns Input Timing Reference Level......0.8V to 2.0V Output Timing Reference Level...............0.8V to 2.0V

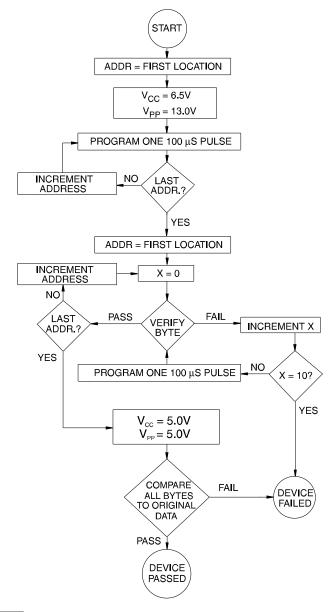
- Notes: 1. V<sub>CC</sub> must be applied simultaneously or before OE/V<sub>PP</sub> and removed simultaneously or after OE/VPP.
  - 2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven — see timing diagram.
  - 3. Program Pulse width tolerance is  $100 \, \mu sec \pm 5\%$ .

### Atmel's 27C512R Integrated **Product Identification Code**

		Pins								Hex
Codes	A0	07	O6	O5	04	О3	O2	O1	00	Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	1	1	0	1	0D

#### Rapid Programming Algorithm

A 100 us CE pulse width is used to program. The address is set to the first location. VCC is raised to 6.5V and OE/VPP is raised to 13.0V. Each address is first programmed with one 100  $\mu$ s  $\overline{CE}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100 µs pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. OE/VPP is then lowered to V<sub>IL</sub> and V<sub>CC</sub> to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.







# **Ordering Information**

tACC	Icc (mA)				
(ns)	Active	Standby	Ordering Code	Package	Operation Range
45	20	0.1	AT27C512R-45JC AT27C512R-45PC AT27C512R-45RC AT27C512R-45TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-45JI AT27C512R-45PI AT27C512R-45RI AT27C512R-45TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
55	20	0.1	AT27C512R-55JC AT27C512R-55PC AT27C512R-55RC AT27C512R-55TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-55JI AT27C512R-55PI AT27C512R-55RI AT27C512R-55TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
70	20	0.1	AT27C512R-70JC AT27C512R-70PC AT27C512R-70RC AT27C512R-70TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-70JI AT27C512R-70PI AT27C512R-70RI AT27C512R-70TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
90	20	0.1	AT27C512R-90JC AT27C512R-90PC AT27C512R-90RC AT27C512R-90TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-90JI AT27C512R-90PI AT27C512R-90RI AT27C512R-90TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
120	20	0.1	AT27C512R-12JC AT27C512R-12PC AT27C512R-12RC AT27C512R-12TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-12JI AT27C512R-12PI AT27C512R-12RI AT27C512R-12TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
150	20	0.1	AT27C512R-15JC AT27C512R-15PC AT27C512R-15RC AT27C512R-15TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)

(continued)

# **Ordering Information** (Continued)

tacc (ns)	Icc (mA)		Oudoring Codo	Dookses	Operation Banga
	Active	Standby	Ordering Code	Package	Operation Range
150	20	0.1	AT27C512R-15JI AT27C512R-15PI AT27C512R-15RI AT27C512R-15TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)

Package Type				
32J	32 Lead, Plastic J-Leaded Chip Carrier (PLCC)			
28P6	28 Lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)			
28R	28 Lead, 0.330" Wide, Plastic Gull Wing Small Outline (SOIC)			
28T	28 Lead, Thin Small Outline Package (TSOP)			

